

SPIE. **DSS** SENSING TECHNOLOGY + APPLICATIONS

Hyperspectral Imaging Standards Workshop

Date: **Wednesday 22 April 2015**

Time: **4:30 PM - 6:00 PM**

Location: **Conv. Ctr. 346**

Workshop Chair: **David Allen**, National Institute of Standards and Technology (USA)

Panel Members: **Ronald Resmini**, MITRE Corporation (USA); **Oliver Weatherbee**, SpecTIR LLC (USA); **Terry Slonecker**, USGS (USA); **Karen Reczek**, National Institute of Standards and Technology (USA)

Panel Moderator: **Karen Reczek**, National Institute of Standards and Technology (USA)

Purpose: Hyperspectral imaging as a field is in the process of maturing from a specialized tool to a routine method applied to many facets of society. Standards provide common reference points that foster an understanding between different entities. This meeting is intended to survey the range of standards currently available and to identify gaps where new standards are needed. The range of standards open for discussion encompass all aspects related to hyperspectral imaging and may include performance specifications, calibration standards, data formats, terminology, and best practices. This workshop will provide an open forum for metrology laboratories, instrument vendors, data product analysts, data product vendors, and end-users. The outcome of this meeting will provide guidance for future activities including an expanded workshop to address areas determined to be significant bottlenecks restricting the full potential of this field. This meeting is open to all DSS registered attendees.

Goals:

- Provide a forum for the hyperspectral imaging community to discuss current and needed standards
- Identifying international standards organizations that are the most logical homes for new standards
- Address the need for standards to address regulatory requirements
- Discuss the possibility of a uniform set of performance metrics
- Discuss the need for traceability to national standards
- Consider formalizing best practices

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